Search Notes



Application/Control No.	Applicant(s)/Patent under Reexamination		
10/767,719	OGAWA, HIDEHIKO		
Examiner	Art Unit		
Thomas D. Lee	2625		

SEARCHED				
Class	Subclass	Date	Examiner	
358	1.15, 402, 440	9/27/2005	TDL	
379	100.01	9/27/2005	TDL	
379	100.08	9/27/2005	TDL	
379	100.13	9/27/2005	TDL	
379	100.17	9/27/2005	TDL	
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updated		2/2/2006	TDL	
updated		7/20/2006	TDL	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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Interferen Prin		7/20/2006	TDL	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
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